L Number	Hits	Search Text	DB	Time stamp
-	66	method and (statistical adj outlier\$1)	USPAT; US-PGPUB	2002/11/01 16:13
-	1	method near2 (statistical adj outlier\$1)	USPAT;	2002/10/28
	2047	//intranct = 0.1	US-PGPUB	20:35
1 -	3247	((integrate\$1 or circuit\$1) near2 die) and (438/\$.ccls. or 257/\$.ccls. or	USPAT; US-PGPUB	2002/10/28
		324/\$.ccls.)	US-PGPUB	21.34
_	8831	(semiconductor or (integrate\$1 near	USPAT;	2002/10/30
	0031	circuit) or substrate or wafer or die)	US-PGPUB	23:11
1		and averag\$3 and (absolute adj value\$1)		
-	42	(((integrate\$1 or circuit\$1) near2 die)	USPAT;	2002/10/28
		and (438/\$.ccls. or 257/\$.ccls. or	US-PGPUB	21:31
		324/\$.ccls.)) and (target and average)		
-	5045	((semiconductor or (integrate\$1 near	USPAT;	2002/10/28
		circuit) or substrate or wafer or die) and averag\$3 and (absolute adj value\$1))	US-PGPUB	21:32
		and averages and (absolute ad) value(1))		
. .	-288	(-((semiconductor-or -(integrate\$1 near -	USPAT; -	2002/10/28
		circuit) or substrate or wafer or die)	US-PGPUB	21:34
		and averag\$3 and (absolute adj value\$1))		
		and calculat\$3 and difference\$1) and		
		(438/\$.ccls. or 257/\$.ccls. or		
1		324/\$.ccls.)		0000 45 5 45 5
_	861	(438/14).CCLS.	USPAT;	2002/10/28
	482	(439/15) CCI S	US-PGPUB	21:53
-	482	(438/15).CCLS.	USPAT; US-PGPUB	2002/10/28
_	571	(438/17).CCLS.	USPAT;	2002/10/28
]	(130/1//.0025.	US-PGPUB	21:53
_	433	(438/460).CCLS.	USPAT;	2002/10/28
			US-PGPUB	21:53
-	45	((438/15).CCLS.) and averag\$3	USPAT;	2002/10/28
	100	//420/17\ GGTG \ and arrange2	US-PGPUB	21:54
-	109	((438/17).CCLS.) and averag\$3	USPAT; US-PGPUB	2002/10/28
_	40	((438/460).CCLS.) and averag\$3	USPAT;	2002/10/28
		((100) 100) 100201, and atologyo	US-PGPUB	21:54
-	169	((438/14).CCLS.) and averag\$3	USPAT;	2002/10/29
			US-PGPUB	20:29
-	1	(US-20020102749-\$).did.	US-PGPUB	2002/10/28
	1	(US-20020066859-\$).did.	He benin	21:56
-	_	(US-20020088839-\$).did.	US-PGPUB	22:01
_	1	(US-6419846-\$).did.	USPAT	2002/10/28
	_	(12 1321111 17 17 17 17 17 17 17 17 17 17 17 17		22:03
-	1	(US-6240329-\$).did.	USPAT	2002/10/28
				22:10
-	8202	(semiconductor or (integrate\$1 near	USPAT;	2002/10/30
		circuit) or substrate or wafer or die) and average and (absolute adj value\$1)	US-PGPUB	23:12
_	1408	(semiconductor or (integrate\$1 near	USPAT;	2002/10/30
	1405	circuit) or substrate or wafer or die)	US-PGPUB	23:14
	,	and (average same (absolute adj value\$1))		
-	2246	quiescent adj current	USPAT;	2002/11/01
	4.5	(US-PGPUB	19:01
-	45	<pre>(quiescent adj current) and average\$1 and (absolute adj value\$1)</pre>	USPAT; US-PGPUB	2002/11/01 16:56
-	922	(quiescent adj current) and (wafer or	USPAT;	2002/11/01
		substrate or chip or die)	US-PGPUB	17:07
-	331	((quiescent adj current) and (wafer or	USPAT;	2002/11/01
		substrate or chip or die)) and variation	US-PGPUB	17:09
-	114	(quiescent adj current) same variation	USPAT;	2002/11/01
	0	idda and (statistiss) near? outliers!	US-PGPUB	18:28
	ا	iddq and (statistic\$2 near2 outlier\$1)	USPAT; US-PGPUB	2002/11/01 18:29
-	93	statistic\$2 near2 outlier\$1	USPAT;	2002/11/01
			US-PGPUB	18:29
-	89	((quiescent adj current) or iddq) same	USPAT;	2002/11/01
		averag\$3	US-PGPUB	19:47

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			,	1
-	533	(leakage adj current) same averag\$3	USPAT;	2002/11/01
		•	US-PGPUB	19:48
-	197	(leakage adj current) same (absolute adj	USPAT;	2002/11/01
		value\$1)	US-PGPUB	19:48
-	14	((leakage adj current) same averag\$3) and	USPAT;	2002/11/01
		((leakage adj current) same (absolute adj	US-PGPUB	19:50
		value\$1))		
_	28785	calculat\$3 near2 difference\$1	USPAT;	2002/11/01
			US-PGPUB	19:51
-	2866	calculat\$3 near2 (absolute adj value\$1)	USPAT;	2002/11/01
			US-PGPUB	19:51
-	24006	calculat\$3 near2 averag\$3	USPAT;	2002/11/01
1		•	US-PGPUB	19:51
l -	290	(calculat\$3 near2 difference\$1) and	USPAT;	2002/11/01
1		(calculat\$3 near2 (absolute adj value\$1))	US-PGPUB	20:03
		and (calculat\$3 near2 averag\$3)		
-	194	((calculat\$3 near2 difference\$1) and	USPAT;	2002/11/01
		(calculat\$3 near2 (absolute adj value\$1))	US-PGPUB	20:08
		and (calculat\$3 near2 averag\$3)) and		
		semiconductor)		
-	40	((calculat\$3 near2 difference\$1) and	USPAT;	2002/11/01
		(calculat\$3 near2 (absolute adj value\$1))	US-PGPUB	20:08
1		and (calculat\$3 near2 averag\$3)) and		
		(wafer or substrate or semiconductor)		